

# JIS

JAPANESE  
INDUSTRIAL  
STANDARD

Translated and Published by  
Japanese Standards Association

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JIS R 2216 : 2005

(TARJ/JSA)

**Methods for X-ray fluorescence  
spectrometric analysis of refractory  
products**

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ICS 81.080

Reference number : JIS R 2216 : 2005 (E)

## Foreword

This translation has been made based on the original Japanese Industrial Standard revised by the Minister of Economy, Trade and Industry through deliberations at the Japanese Industrial Standards Committee as the result of proposal for revision of Japanese Industrial Standard submitted by The Technical Association of Refractories, Japan (TARJ)/Japanese Standards Association (JSA) with the draft being attached, based on the provision of Article 12 Clause 1 of the Industrial Standardization Law applicable to the case of revision by the provision of Article 14.

Consequently **JIS R 2216** : 1995 is replaced with this Standard.

This revision has been made based on **ISO 12677** : 2003 *Chemical analysis of refractory products by XRF—Fused cast bead method* for the purpose of making it easier to compare this Standard with International Standard; to prepare Japanese Industrial Standard conforming with International Standard; and to propose a draft of an International Standard which is based on Japanese Industrial Standard.

Attention is drawn to the possibility that some parts of this Standard may conflict with a patent right, application for a patent after opening to the public, utility model right or application for registration of utility model after opening to the public which have technical properties. The relevant Minister and the Japanese Industrial Standards Committee are not responsible for identifying the patent right, application for a patent after opening to the public, utility model right or application for registration of utility model after opening to the public which have the said technical properties.

Date of Establishment: 1987-03-01

Date of Revision: 2005-06-20

Date of Public Notice in Official Gazette: 2005-06-20

Investigated by: Japanese Industrial Standards Committee  
Standards Board  
Technical Committee on Ceramics

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JIS R 2216 : 2005, First English edition published in 2006-08

Translated and published by: Japanese Standards Association  
4-1-24, Akasaka, Minato-ku, Tokyo, 107-8440 JAPAN

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In the event of any doubts arising as to the contents,  
the original JIS is to be the final authority.

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Printed in Japan

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## Methods for X-ray fluorescence spectrometric analysis of refractory products

**Introduction** This Japanese Industrial Standard has been prepared based on the first edition of **ISO 12677** *Chemical analysis of refractory products by XRF—Fused cast bead method* published in 2003 with some modifications of the technical contents.

The portions given sidelines or dotted underlines are the matters modified from the original International Standard. A list of modifications with the explanations is given in Annex 10 (informative).

**1 Scope** This Standard specifies methods for X-ray fluorescence spectrometric analysis of oxides in refractory products and materials by means of the glass bead method.

Remarks : The International Standard corresponding to this Standard is as follows.

In addition, symbols which denote the degree of correspondence in the contents between the relevant International Standard and **JIS** are IDT (identical), MOD (modified), and NEQ (not equivalent) according to **ISO/IEC Guide 21**.

ISO 12677:2003 *Chemical analysis of refractory products by XRF—Fused cast bead method* (MOD)

**2 Normative references** The following standards contain provisions which, through reference in this text, constitute provisions of this Standard. The most recent editions of the standards (including amendments) indicated below shall be applied.

JIS K 0050 *General rules for chemical analysis*

JIS K 0119 *General rules for X-ray fluorescence spectrometric analysis*

JIS K 0211 *Technical terms for analytical chemistry (General part)*

JIS K 0215 *Technical terms for analytical chemistry (Analytical instrument part)*

JIS Q 0034 *General requirements for the competence of reference material producer*

JIS Q 0035 *Certification of reference materials—General and statistical principles*

JIS R 1301 *Porcelain crucibles for chemical analysis*

JIS R 2012 *Methods for chemical analysis of refractories containing zircon and/or zirconia*

JIS R 2013 *Methods for chemical analysis of refractories containing alumina, zirconia and silica*